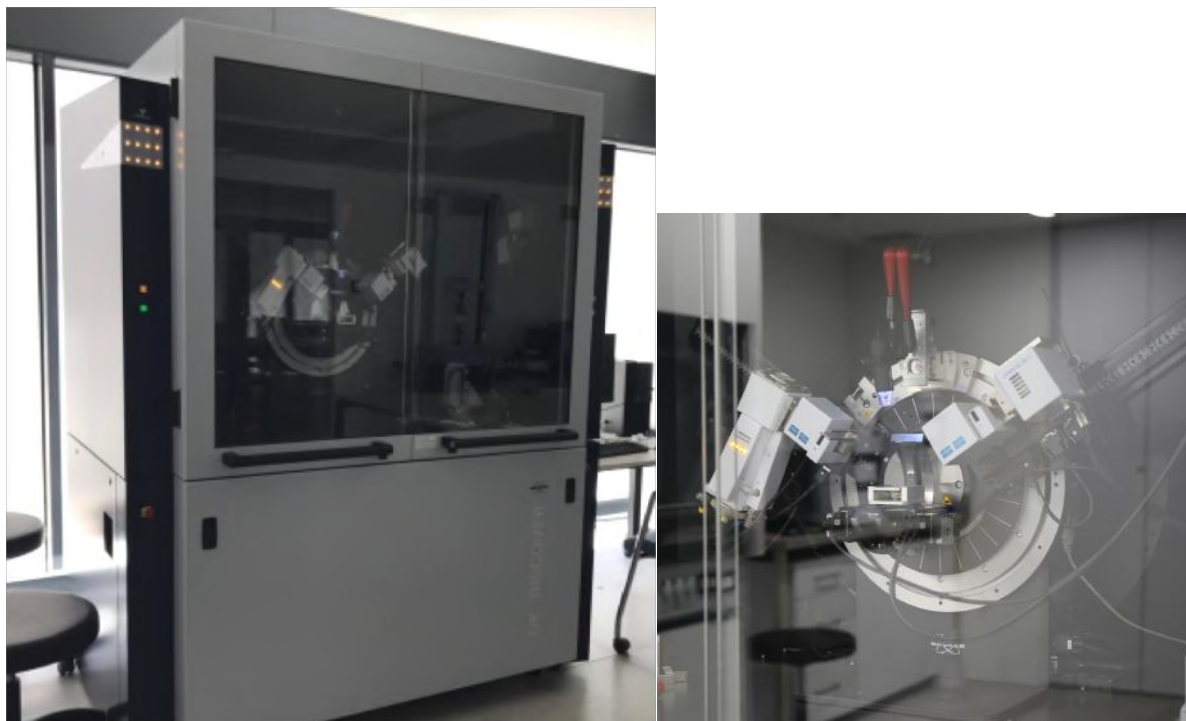


X-RAY DIFFRACTOMETER (XRD)



Intended Use of the Instrument: Crystallographic analysis of materials

Instrument Brand/Model: Bruker D8 Discover

AGU CRF Thematic Laboratory: Nano Imaging and Analysis Laboratory

Location of the Instrument: AGU-CRF LAB 15

Academic Director(s) of the Instrument:

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Responsible Specialists of the Instrument:

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X-ray diffractometry is a technique to determine interspace distances and orientations between the atoms of crystalline materials. X-ray diffracts with varying angles depending on the crystal structure and diffraction pattern of the material is formed. XRD has a broad application range for investigating crystalline and amorphous materials, analysis of metals and their alloys, composition analysis of thin films, analysis of polymers.